

Computation of waveform parameter uncertainties

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN 62754:2017 sisaldab Euroopa standardi EN 62754:2017 ingliskeelset teksti.	This Estonian standard EVS-EN 62754:2017 consists of the English text of the European standard EN 62754:2017.
Standard on jõustunud sellekohase teate avaldamisega EVS Teatajas	This standard has been endorsed with a notification published in the official bulletin of the Estonian Centre for Standardisation.
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English Version

Computation of waveform Parameter uncertainties (IEC 62754:2017)

Calcul des incertitudes des paramètres des formes d'onde
(IEC 62754:2017)

Berechnung der Messunsicherheiten von
Schwingungsabbildparametern
(IEC 62754:2017)

This European Standard was approved by CENELEC on 2017-06-28. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 85/585/FDIS, future edition 1 of IEC 62754, prepared by IEC/TC 85 "Measuring equipment for electrical and electromagnetic quantities" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62754:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-03-28
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-06-28

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Endorsement notice

The text of the International Standard IEC 62754:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated :

IEC 60359:2001

NOTE

Harmonized as EN 60359:2002.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60469	2013	Transitions, pulses and related waveforms - Terms, definitions and algorithms	EN 60469	2013

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